

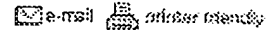
Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7870	((257/295,e27.048,e27.084,e27.104,e29.164,e29.272,e29.342,e29.343,e21.208,e21.663,e21.664) or (438/3) or (365/145) or (501/134)).CCLS.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:22
L2	3744	1 and ferroelectric	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:22
L3	3317	2 and (@ad<"20030204" or @rlad<"20030204")	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L4	2689	3 and capacitor	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L5	2305	4 and electrode	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L6	1820	3 and (ferroelectric same capacitor same electrode)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:24
L7	352	6 and pzt and plzt	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:24
L8	15	("20020015852"   "20020153543"   "5387459"   "5656382"   "5719417"   "5850089"   "5998236"   "6090443"   "6229166"   "6258459"   "6376090"   "6385355"   "6411017"   "6511161"   "6526833").PN. OR ("6841817").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 09:33

L9	59	("0476274"   "2490547"   "2622184"   "2801322"   "2925329"   "3190262"   "3404873"   "3520416"   "3549412"   "3659402"   "3823926"   "3969449"   "4036915"   "4080926"   "4288396"   "4529427"   "4833976"   "4842893"   "4847469"   "4954371"   "5034372"   "5097800"   "5110622"   "5120703"   "5139999"   "5165960"   "5204314"   "5225561"   "5248787"   "5259995"   "5280012"   "5376409"   "5536323"   "5554866").PN. OR ("5998236").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 09:52
L10	78	("2695396"   "2992929"   "3529978"   "3977887"   "4144591"   "4149301"   "4244722"   "4360896"   "4503482"   "4697222"   "4792463"   "4917810"   "4918350"   "4978646"   "5046043"   "5109771"   "5122923"   "5146299"   "5369068").PN. OR ("5519234"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 10:55
L11	16	("5426075"   "5434102"   "5468679"   "5519234"   "5784310"   "5824590"   "5833745"   "5902639").PN. OR ("6194227").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:02
L12	14	("5146299"   "5478653"   "5519234"   "5576564"   "5780886").PN. OR ("5989927"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:04
L13	29	("4786837"   "5247189"   "5519234"   "5578867").PN. OR ("5736759").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:10
L14	16	("5736759"   "5833745"   "5994153"   "6043526").PN. OR ("6153898").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:14

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| <input type="checkbox"/> | <b>4. Effect of interconnect layer on Pb(Zr,Ti)O<sub>3</sub> thin film capacitor degradation</b><br>Kobayashi, S.; Amanuma, K.; Hada, H.;<br>Electron Device Letters, IEEE<br>Volume 19, Issue 11, Nov. 1998 Page(s):417 - 419<br><a href="#">AbstractPlus</a>   <a href="#">References</a>   Full Text: <a href="#">PDF(48 KB)</a> IEEE JNL  |
| <input type="checkbox"/> | <b>5. Quantitative determination of the dielectric constant of the interfacial layer in PZT ferroelectric capacitors</b><br>Bartic, A.T.; Wouters, D.J.; Jin Sing; Norga, G.; Bender, H.; Maes, H.E.;<br>Applications of Ferroelectrics, 1998. ISAF 98. Proceedings of the Eleventh IEEE International Symposium on<br>24-27 Aug. 1998 Page(s):73 - 76<br><a href="#">AbstractPlus</a>   Full Text: <a href="#">PDF(356 KB)</a> IEEE CNF          |
| <input type="checkbox"/> | <b>6. Effect of crystallisation on fatigue in sol-gel PZT ferroelectric capacitors with reactively sputtered RuO<sub>2</sub> electrode layers</b><br>Norga, G.J.; Wouters, D.J.; Bartic, A.; Fe, L.; Maes, H.E.;<br>Applications of Ferroelectrics, 1998. ISAF 98. Proceedings of the Eleventh IEEE International Symposium on<br>24-27 Aug. 1998 Page(s):3 - 6<br><a href="#">AbstractPlus</a>   Full Text: <a href="#">PDF(324 KB)</a> IEEE CNF |
| <input type="checkbox"/> | <b>7. Pulsed laser deposition of metallic oxide thin films for microelectronic applications</b><br>Varela, M.; Trtik, V.; Guerrero, C.; Roldan, J.; Benitez, F.; Ferrater, C.; Sanchez, F.; Bibes, M.; Rubi, R.;  |

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